

ADVANCED IC PACKAGING USING SILICON INTERCONNECT FABRIC

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Abstract

The ever-growing demand for data-bandwidth is pushing boundaries of traditional IC packaging technologies. Moreover, the slow-down of Moore's law has accelerated a paradigm shift in packaging technologies, assembly techniques, and heterogeneous integration solutions for system scaling. The Silicon-Interconnect Fabric (Si-IF) technology is a silicon-based, package-less, fine-pitch, highly scalable, heterogeneous integration platform that uses unpackaged dielets to be assembled at small inter-dielet spacings ($\leq 100 \mu\text{m}$) using fine-pitch ($\leq 10 \mu\text{m}$) interconnects. These fine-pitch interconnects are made possible using a solder-less direct metal-metal (gold-gold and copper-copper) thermal compression bonding that have low specific contact resistance of $\leq 0.7 \Omega\text{-}\mu\text{m}^2$. Therefore, this integration scheme allows for a large number of parallel, short, on-chip like data-links ($\leq 500 \mu\text{m}$) between dielets. As a result, simple IOs can transfer data between dies using a Simple Universal Parallel intERface for chips (SuperCHIPS) at low latency ($< 30 \text{ ps}$), low energy per bit ($\leq 0.03 \text{ pJ/b}$), and high data- rates (up to 10 Gbps/link), corresponding to an aggregate bandwidth of $\geq 8 \text{ Tbps/mm}$. These benefits were experimentally demonstrated to provide 8-30X reduction in latency, 5-90X improvement in data-bandwidth, and 5-40X improvement in energy per bit compared to existing integration schemes.